

**Search Notes****Application/Control No.**

10/646,708

**Examiner**

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**Applicant(s)/Patent under Reexamination**

ECKER ET AL.

**Art Unit**

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	227.14, 227.16	12/12/2005	PL
385	10, 12	12/12/2005	PL
385	13, 37	12/12/2005	PL
Updated	search	5/30/2006	PL
Updated	search	10/30/2006	PL
Updated	search	5/15/2007	PL
Updated	search	5/18/2007	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted w/ S. Allen	8/4/2005	PL
Consulted w/ B. Healy AU 2883 CL 385	8/9/2005	PL
East (See attached)	8/9/2005	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	12/12/2005	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	5/30/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	10/30/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	5/15/2007	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	5/18/2007	PL